

Notice of References Cited	Application/Control No. 10/708,715		Applicant(s)/Patent Under Reexamination BARD ET AL.	
	Examiner Sun J. Lin		Art Unit 2825	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0182640 A1	09-2003	Alani et al.	716/4
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
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FOREIGN PATENT DOCUMENTS

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Karlsson et al., "Analytical Extraction Method for Submicron MOS Transistor Model Parameters in the Linear Region", Dec. 1994, IEEE Proceedings on Circuits, Devices and Systems, vol. 141, iss. 6, pp. 457 - 461.
	V	Assenmacher, "BSIM 4 Modeling and Parameter Extraction", Jan. 2003, Infineon Technologies AG, Presentation View Graphs, pp. 1 - 23.
	W	Xi et al., "BSIM4.5.0 Enhancements", Jun. 2005, University of California-Berkeley, Presentation Vie Graphs, pp. 1 - 9.
	X	Polishchuk et al., "CMOS Vt-Control Improvement Through Implant Lateral Scatter Elimination", Sept. 2005, IEEE International Symposium on Semiconductor Manufacturing, Paper Digest, pp. 193 - 196.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	"BSIM4.5.0. Manual: Chapter 14: Well Proximity Effect Model", 2005, University of California-Berkeley, 14-1 - 14-7.
	V	
	W	
	X	

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